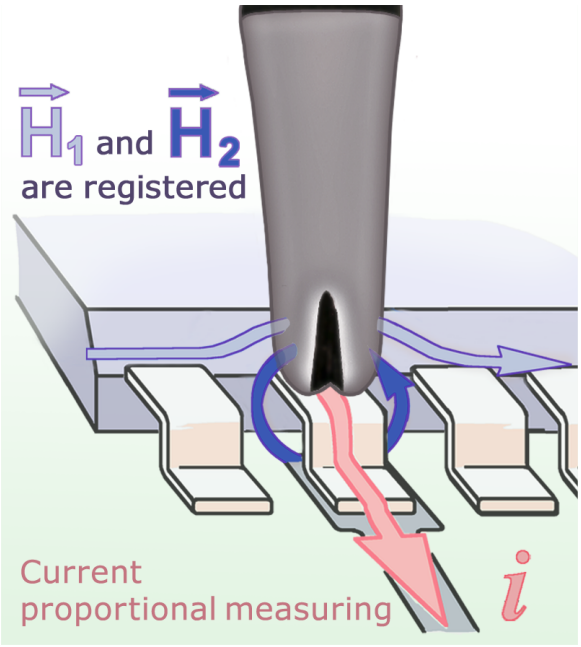
XF-U 2.5-1

H-Field Probe 30 MHz up to 6 GHz



Short description

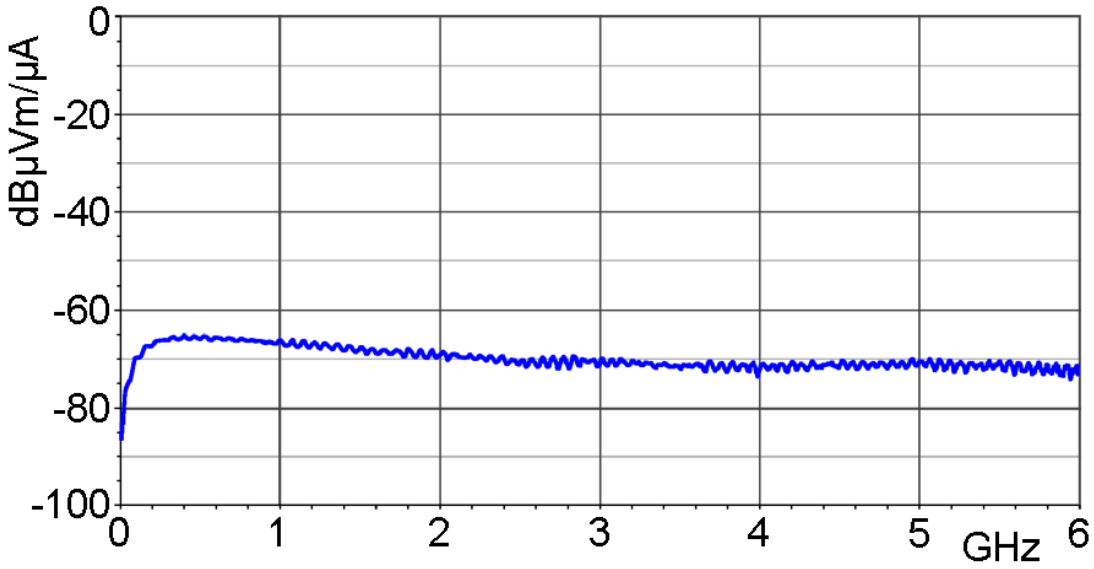
The XF-U 2.5-2 near-field probe is designed for the selective measurements of RF currents in conducting paths, component connectors, SMD components, and IC pins. The probe head has a magnetically active gap with an approx. width of 0.5 mm. To use, the head should be positioned directly onto the measured object.

The XF-U 2.5-2 is a passive near-field probe that is designed for SMD components (pins). The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

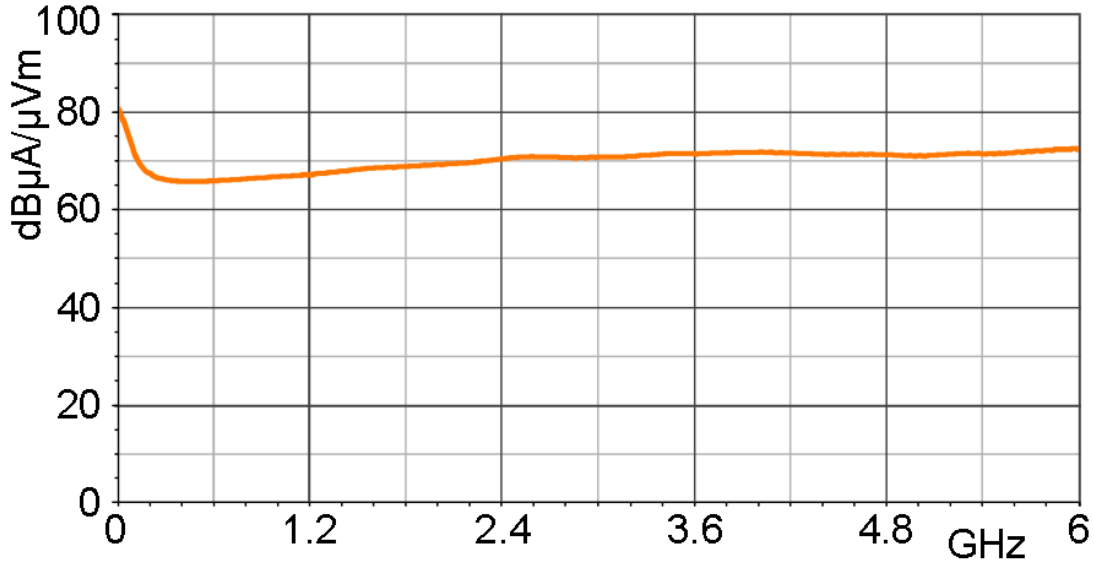
Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 0.5 mm
Probe head dimensions:	Ø ≈ 4 mm
Connector - output	SMA, female, jack
Weight	15 g

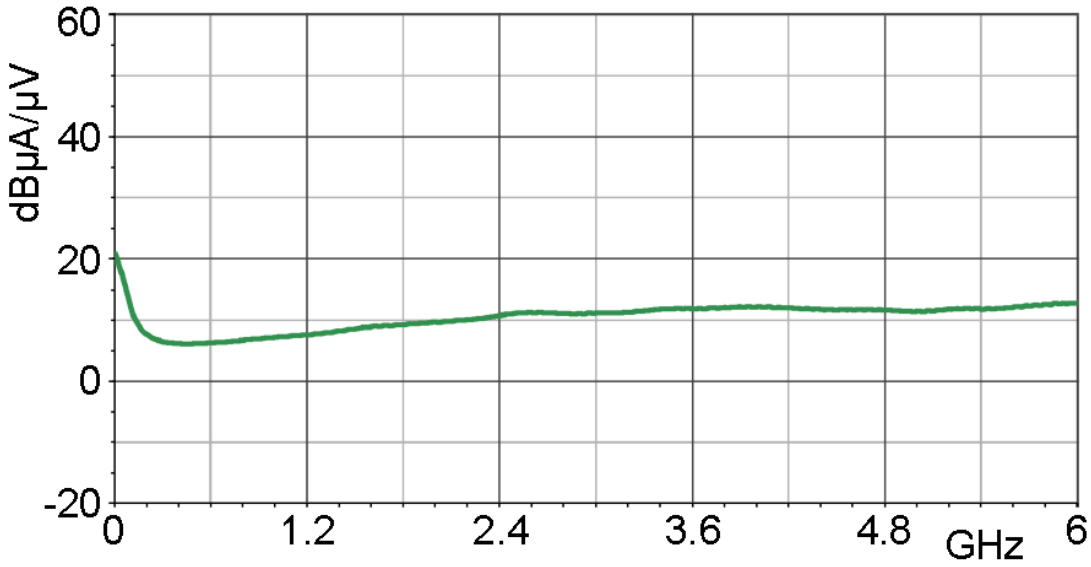
Frequency response [dBµV] / [dBµA/m]



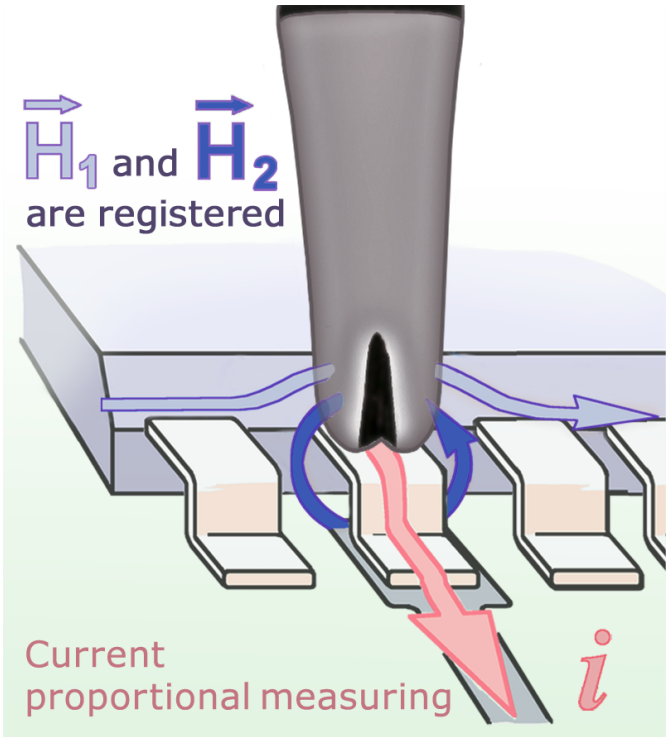
H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



Measuring principles



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Probe head